

# MICROELECTRONICS AND RELIABILITY

**An International Journal & World Abstracting Service**

**Volume 31, 1991**

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**PERGAMON PRESS**

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# MICROELECTRONICS AND RELIABILITY

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(contributors from India should refer to the Notes for Contributors on the inside back cover)

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## TWELVE ISSUES PUBLISHED PER ANNUM (FROM VOLUME 32, 1992)

### Publishing, Subscription and Advertising Offices:

Headington Hill Hall, Oxford, OX3 0BW (Tel: (0865) 794141; Fax: (0865) 60285)

### Annual subscription rates 1992

Annual institutional subscription rate (1992): £585.00 (U.S.\$935.00). Two-year institutional rate (1992/93): £1111.50 (U.S.\$1776.50). Sterling prices are definitive. U.S. dollar prices are quoted for convenience only, and are subject to exchange rate fluctuation. Prices include postage and insurance and are subject to change without notice. Subscription rates for Japan are available on request. Subscription enquiries from customers in North America should be sent to: Pergamon Press Inc., 395 Saw Mill River Road, Elmsford, NY 10523, U.S.A., and for the remainder of the world to: Pergamon Press plc, Headington Hill Hall, Oxford OX3 0BW, U.K. Tel: (0865) 794141; Fax: (0865) 60285.

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The Item-Fee Code for this publication is: 0026-2714/91 \$3.00 + .00

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